

Search Notes

Application/Control No.

10/785,259

Examiner

B. Chen

Applicant(s)/Patent under
Reexamination

OHKAWA ET AL.

Art Unit

1762

SEARCHED

Class	Subclass	Date	Examiner
427	255.29 255.31	6/21/2005	BC
	376.2		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
west	6/21/2005	BC